

Application No.

O9/964,151

Examiner

John B. Vigushin

Applicant(s)

BOYLAN ET AL.

Art Unit

1 of 2

	SEAR	CHED	
	1		
Class	Subclass	Date	Examiner
361	91.1, 767- 771, 777- 779, 782,	7/1/2002	JBV
	783-785,		-
	790, 791,		
	803		
257	664, 691,	7/1/2002	JBV
	698, 700,		<u>.</u>
	723, 724,		
	728, 786		
333	33, 247	7/1/2002	JBV
324	765	7/1/2002	JBV
363	144, 146,	7/1/2002	JBV
	147		
Search	Updated	3/4/2003	JBV
Search	Updated	12/5/2003	JBV

Class	Subclass	Date	Examine
361	767, 772,	4/1/2004	JBV
	782, 783		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Text Search (see print-out)	7/1/2002	JBV
EAST Text Search (see print-out)	3/4/2003	JBV
EAST Text Search (see print-out); includes text search for teachings that pin sockets are a source of circuit noise.	12/5/2003	JBV
EAST Text Search (see print-out)	4/1/2004	JBV

Search	Notes	(continued)

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09/964,151	BOYLAN ET	AL.
Examiner	Art Unit	
John B. Vigushin	2827	2 of 2

	SEAR	CHED	
Class	Subclass	Date	Examiner
361	772	4/1/2004	JBV
		•	

INT	ERFERENC	E SEARCH	HED
Class	Subclass	Date	Examiner
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(INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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